

FAST GATE TURN-OFF THYRISTORS

Thyristors in SOT-93 envelopes capable of being turned both on and off via the gate. They are suitable for use in high-frequency inverters, power supplies, motor control etc. The devices have no reverse blocking capability; for reverse blocking operation use with a series diode, for reverse conducting operation use with an anti-parallel diode. The anode is connected to the mounting base.

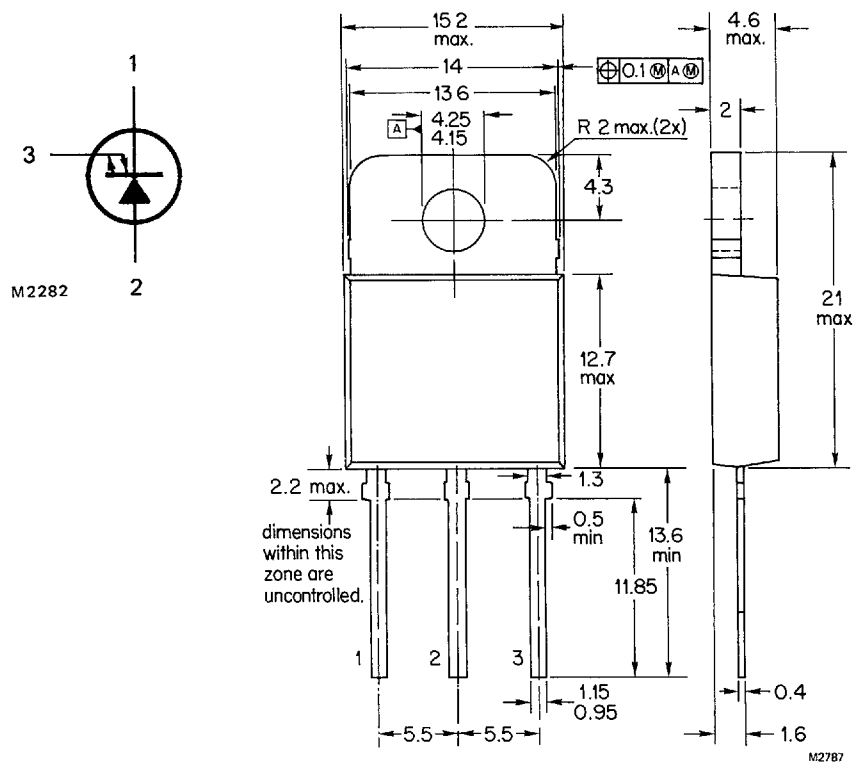
QUICK REFERENCE DATA

		BTS59-850R	1000R	1200R	
Repetitive peak off-state voltage	V_{DRM}	max. 850	1000	1200	V
Non-repetitive peak on-state current	I_{TSM}	max.	100		A
Controllable anode current	I_{TCRM}	max.	50		A
Average on-state current	$I_{T(AV)}$	max.	15		A
Fall time	t_f	<	250		ns

MECHANICAL DATA

Dimensions in mm

Fig.1 SOT-93; anode connected to mounting base



Accessories supplied on request: see data sheets Mounting instructions and accessories for SOT-93 envelopes.

RATINGS

Limiting values in accordance with the Absolute Maximum System (IEC134)

		BTS59-850R			1000R	1200R	
		max.	1000	1100			
Anode to cathode							
Transient off-state voltage	V_{DSM}	max.	1000	1100	1300		V*
Repetitive peak off-state voltage	V_{DRM}	max.	850	1000	1200		V*
Working off-state voltage	V_{DW}	max.	600	800	1000		V*
Continuous off-state voltage	V_D	max.	500	650	750		V*
Average on-state current (averaged over any 20 ms period) up to $T_{mb} = 85\text{ }^\circ\text{C}$		$I_{T(AV)}$	max.		15		A
Controllable anode current		I_{TCRM}	max.		50		A
Non-repetitive peak on-state current $t = 10\text{ ms}$; half-sinewave; $T_j = 120\text{ }^\circ\text{C}$ prior to surge		I_{TSM}	max.		100		A
$I^2 t$ for fusing; $t = 10\text{ ms}$		$I^2 t$	max.		50		A^2s
Total power dissipation up to $T_{mb} = 25\text{ }^\circ\text{C}$		P_{tot}	max.		105		W
Gate to cathode							
Repetitive peak current $T_j = 120\text{ }^\circ\text{C}$ prior to surge gate-cathode forward; $t = 10\text{ ms}$; half-sinewave		I_{GFM}	max.		25		A
gate-cathode reverse; $t = 20\text{ }\mu\text{s}$		I_{GRM}	max.		25		A
Average power dissipation (averaged over any 20 ms period)		$P_{G(AV)}$	max.		5.0		W
Temperatures							
Storage temperature		T_{stg}			-40 to +125		$^\circ\text{C}$
Operating junction temperature		T_j	max.		120		$^\circ\text{C}$
THERMAL RESISTANCE							
From mounting base to heatsink; with heatsink compound		$R_{th\text{ mb-h}}$	=		0.2		K/W
From junction to mounting base		$R_{th\text{ j-mb}}$	=		0.9		K/W

* Measured with gate-cathode connected together.

CHARACTERISTICS

Anode to cathode

On-state voltage

$$I_T = 10 \text{ A}; I_G = 0.5 \text{ A}; T_j = 120 \text{ }^\circ\text{C}$$

$$V_T < 2.3 \text{ V}^*$$

Rate of rise of off-state voltage that will not trigger any off-state device; exponential method

$$V_D = 2/3 V_{Dmax}; V_{GR} = 5 \text{ V}; T_j = 120 \text{ }^\circ\text{C}$$

$$dV_D/dt < 10 \text{ kV}/\mu\text{s}$$

Rate of rise of off-state voltage that will not trigger any device following conduction, linear method

$$I_T = 20 \text{ A}; V_D = V_{DRMmax}; V_{GR} = 10 \text{ V}; T_j = 120 \text{ }^\circ\text{C}$$

$$dV_D/dt < 1.0 \text{ kV}/\mu\text{s}$$

Off-state current

$$V_D = V_{Dmax}; T_j = 120 \text{ }^\circ\text{C}$$

$$I_D < 5.0 \text{ mA}$$

Latching current; $T_j = 25 \text{ }^\circ\text{C}$

$$I_L \text{ typ. } 1.5 \text{ A}^{**}$$

Gate to cathode

Voltage that will trigger all devices

$$V_D = 12 \text{ V}; T_j = 25 \text{ }^\circ\text{C}$$

$$V_{GT} > 1.5 \text{ V}$$

Current that will trigger all devices

$$V_D = 12 \text{ V}; T_j = 25 \text{ }^\circ\text{C}$$

$$I_{GT} > 300 \text{ mA}$$

Minimum reverse breakdown voltage

$$I_{GR} = 1.0 \text{ mA}$$

$$V_{(BR)GR} > 10 \text{ V}$$

Switching characteristics (resistive load)

Turn-on when switched to $I_T = 10 \text{ A}$ from $V_D = 250 \text{ V}$

with $I_{GF} = 1.5 \text{ A}; T_j = 25 \text{ }^\circ\text{C}$

delay time

$$t_d < 0.3 \text{ } \mu\text{s}$$

rise time

$$t_r < 1.5 \text{ } \mu\text{s}$$

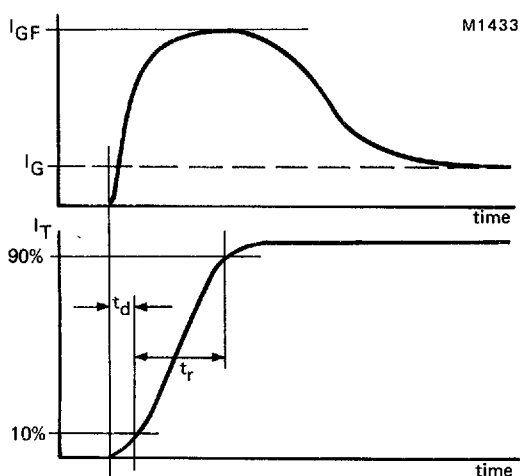


Fig.2 Waveforms

* Measured under pulse conditions to avoid excessive dissipation.

** Below latching level the device behaves like a transistor with a gain dependent on current.

Switching characteristics (inductive load)

Turn-off when switched from $I_T = 10\text{ A}$ to $V_D = V_{D\text{max}}$:

$V_{GR} = 10\text{ V}$; $L_G \leq 0.5\ \mu\text{H}$; $L_S \leq 0.25\ \mu\text{H}$; $C_S \geq 20\text{ nF}$; $T_j = 25\text{ }^\circ\text{C}$

storage time	t_s	<	0.60	μs
fall time	t_f	<	0.25	μs
peak reverse gate current	I_{GR}	<	10	A

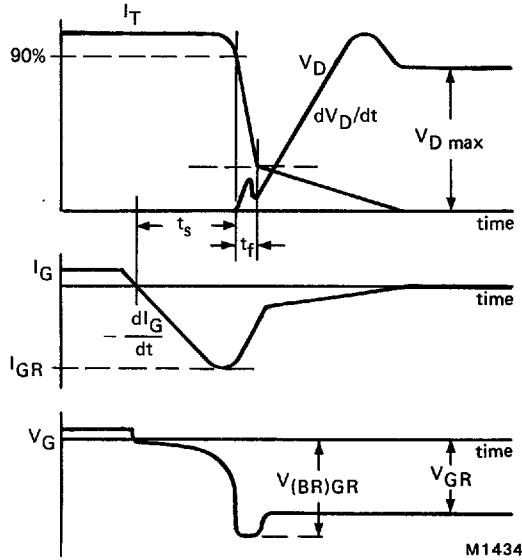


Fig.3 Waveforms.

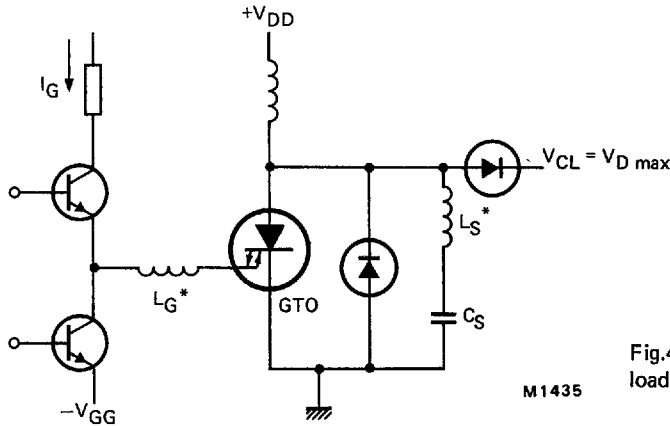


Fig.4 Inductive load test circuit.

*Indicates stray series inductance only

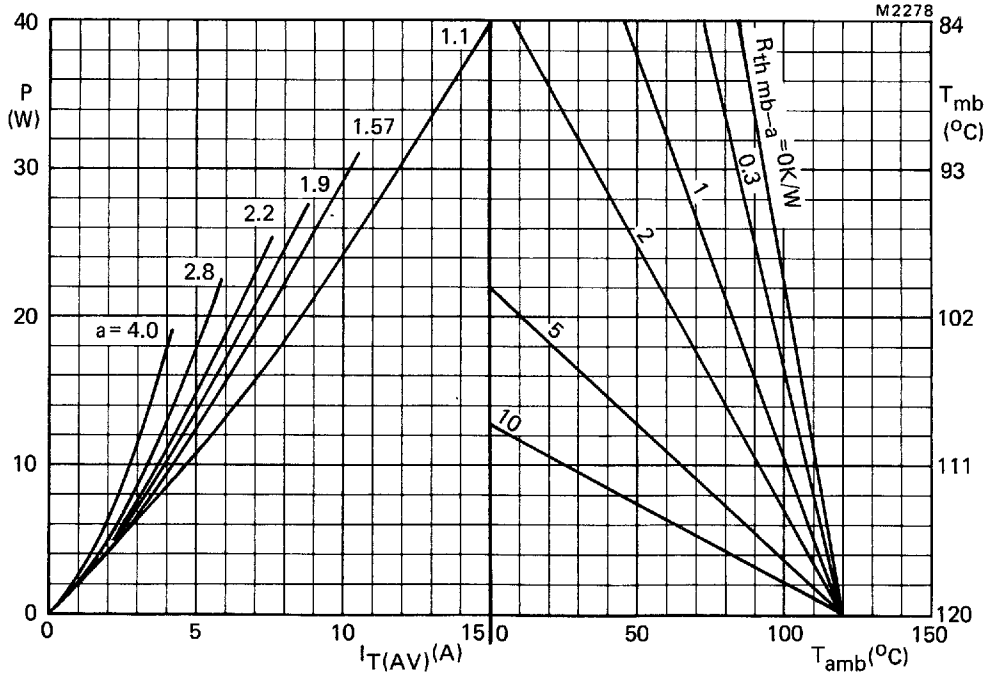


Fig.5 The right hand part shows the interrelationship between the power (derived from the left-hand part) and the maximum permissible temperatures.

$$a = \text{form factor} = \frac{I_T(\text{RMS})}{I_T(\text{AV})}$$

P = power excluding switching losses.

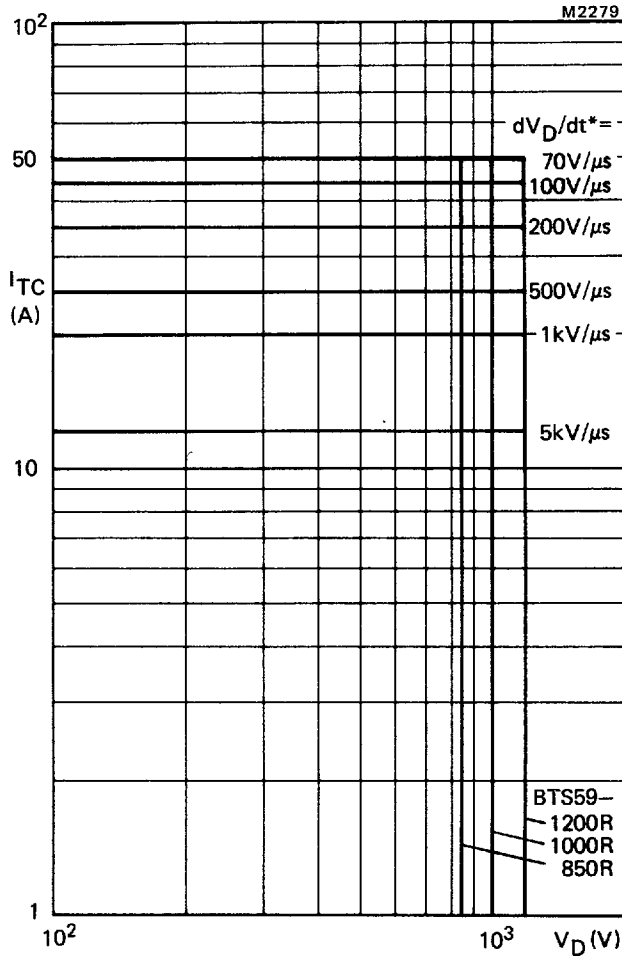


Fig.6 Anode current which can be turned off versus anode voltage; inductive load; $V_{GR} = 10$ V; $L_G \leq 0.5$ μ H; $L_S \leq 0.25$ μ H; $T_j = 120$ °C.
 * dV_D/dt is calculated from I_T/C_S .

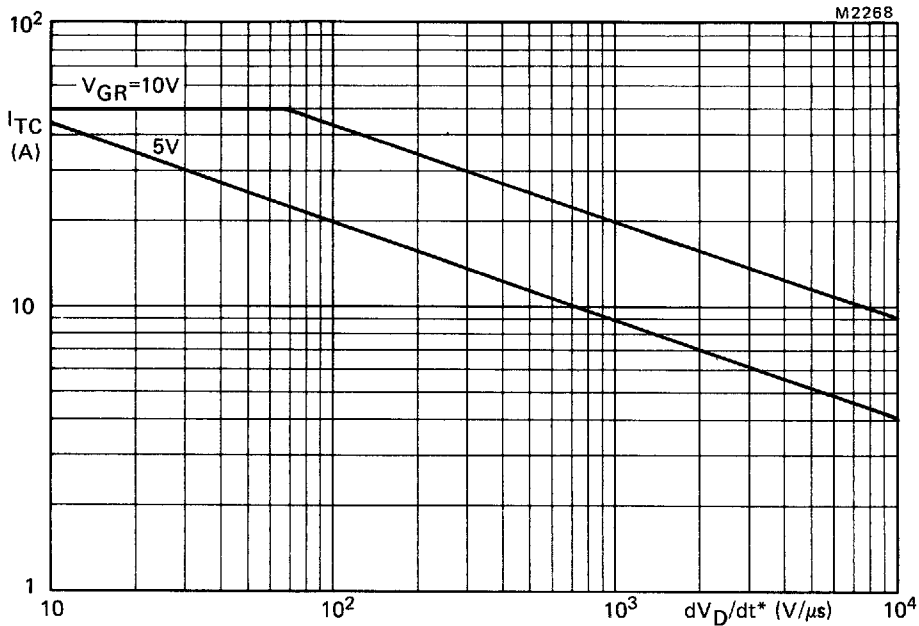


Fig.7 Anode current which can be turned off versus applied dV_D/dt^* ; inductive load;
 $L_G \leq 0.5 \mu H$; $L_S \leq 0.25 \mu H$; $T_j = 120 \text{ }^\circ\text{C}$. * dV_D/dt is calculated from I_T/C_S .

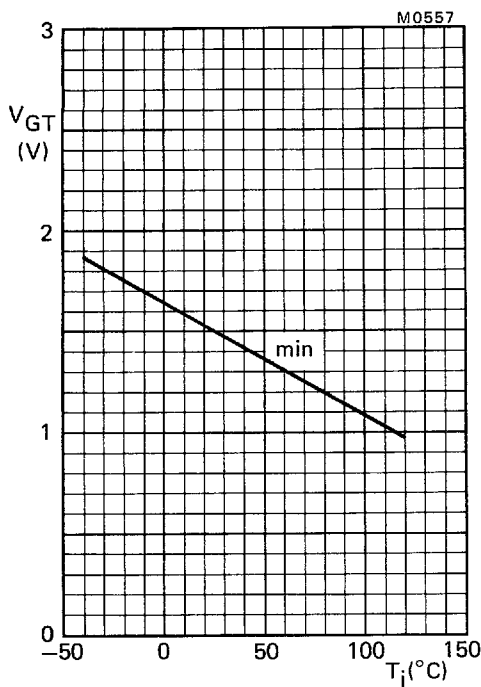


Fig.8 Minimum gate voltage that will trigger all devices as a function of junction temperature; $V_D = 12$ V.

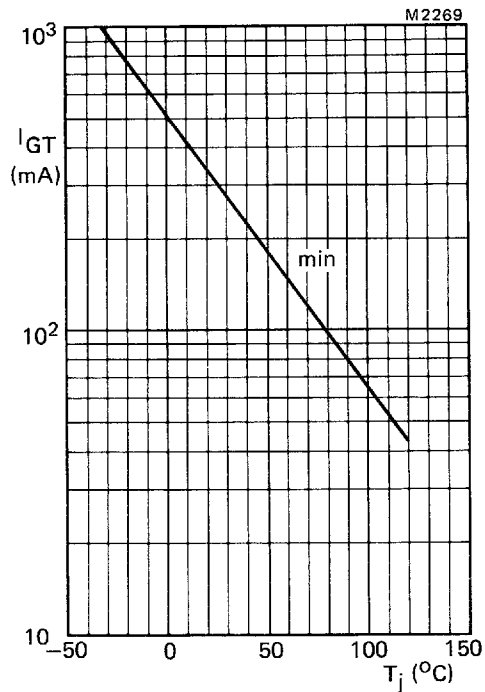


Fig.9 Minimum gate current that will trigger all devices as a function of junction temperature; $V_D = 12$ V.

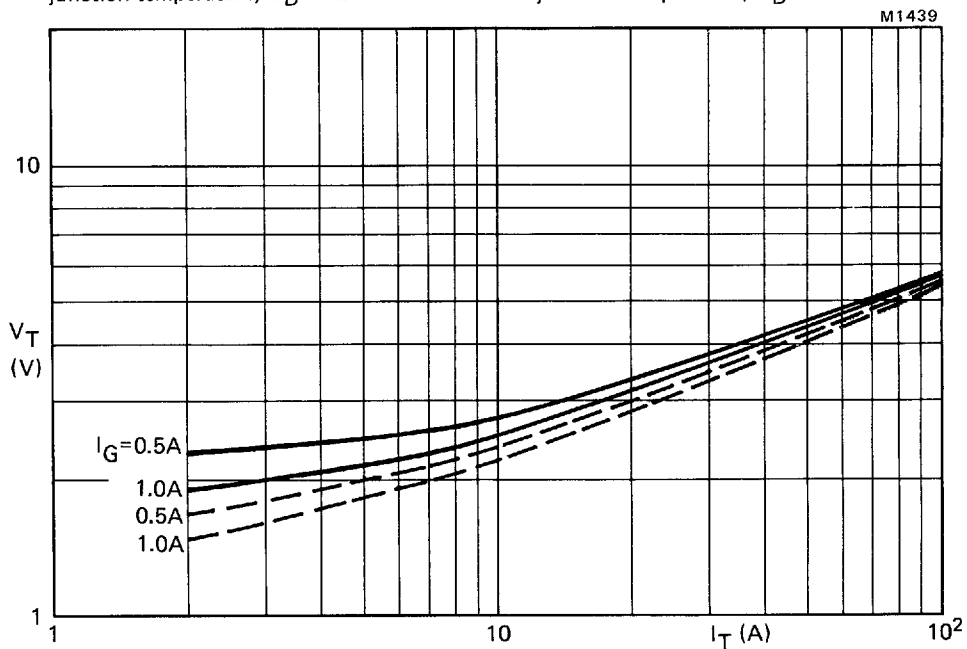


Fig.10 Maximum V_T versus I_T ; — $T_j = 25$ °C; - - - $T_j = 120$ °C.

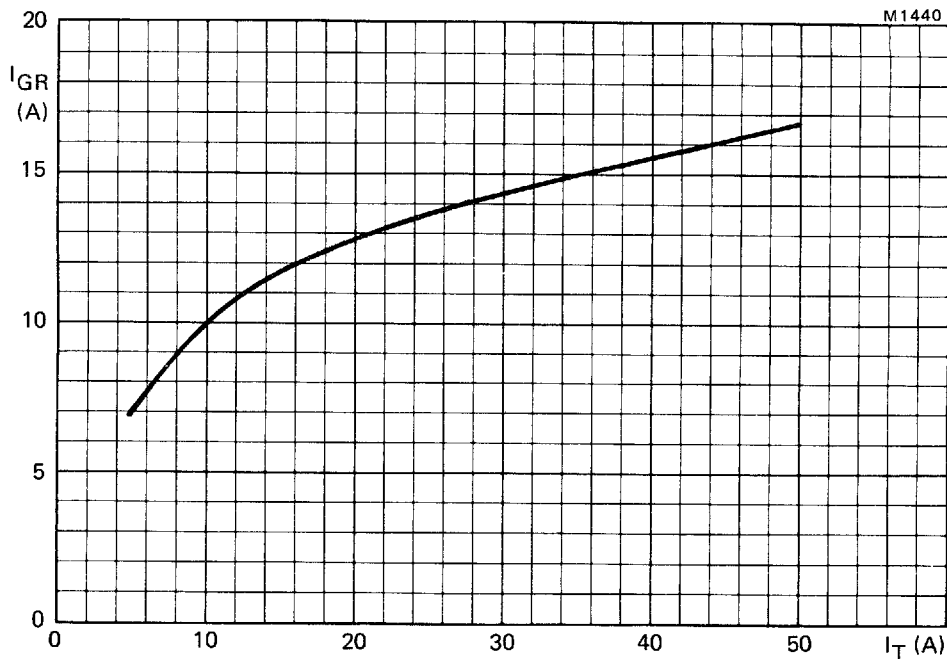


Fig. 11 Peak reverse gate current versus anode current at turn-off; inductive load; $V_{GR} = 10$ V; $I_G = 0.5$ A; $L_G = 0.4$ μ H; $T_j = 120$ $^{\circ}$ C; maximum values.

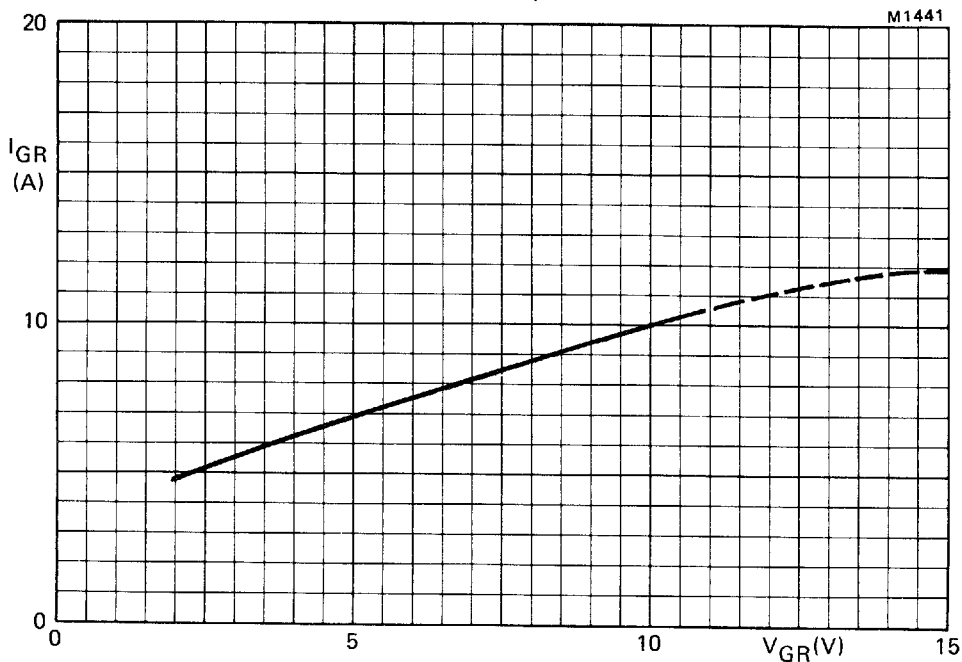


Fig. 12 Peak reverse gate current versus applied reverse gate voltage; inductive load; $I_T = 10$ A; $I_G = 0.5$ A; $L_G = 0.4$ μ H; $T_j = 120$ $^{\circ}$ C; maximum values.

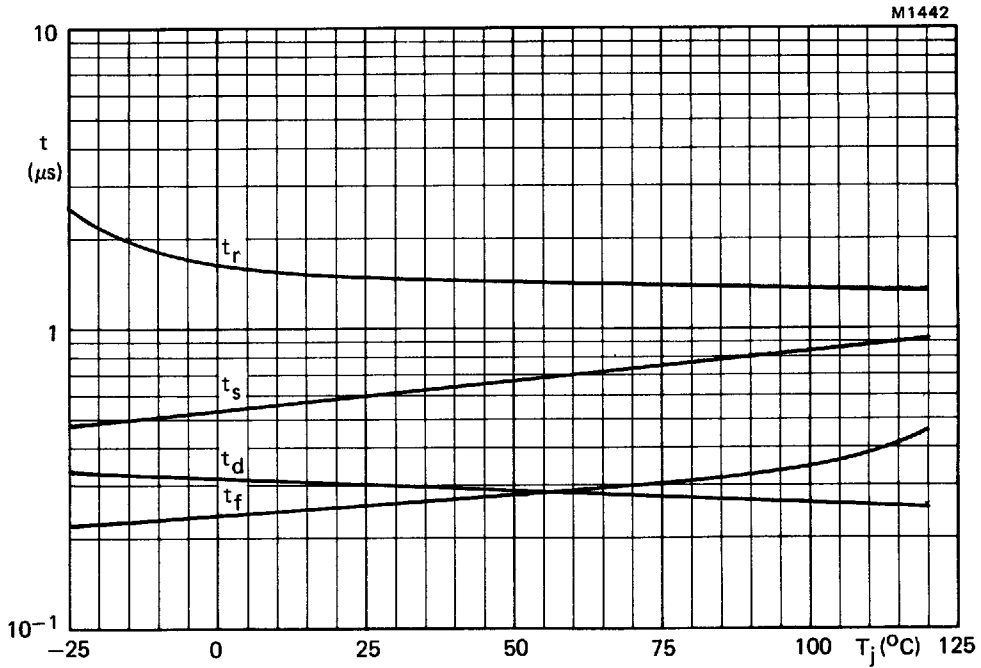


Fig. 13 Switching times as a function of junction temperature; $V_D \geq 250$ V; $I_T = 10$ A; $I_{GF} = 1.0$ A; $V_{GR} = 10$ V; $I_G = 0.5$ A; $L_G = 0.4$ μH; maximum values.

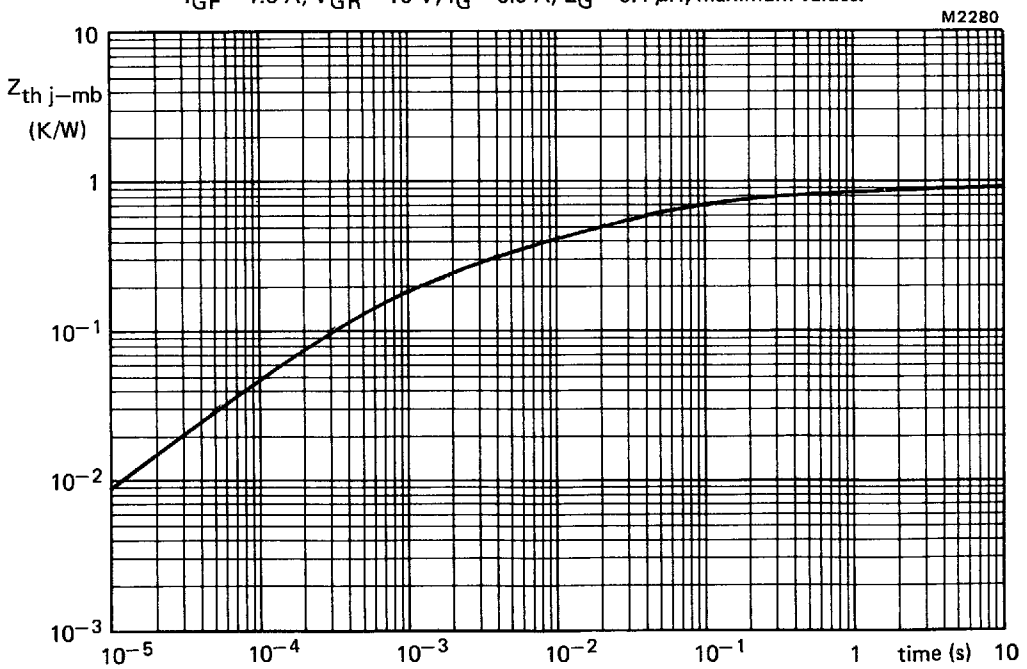


Fig. 14 Transient thermal impedance.

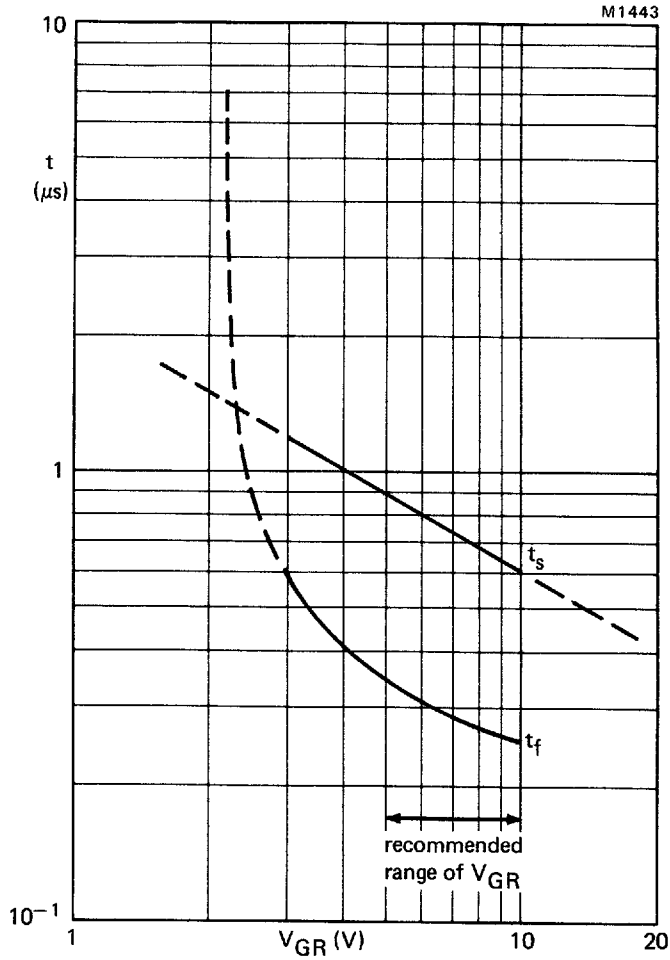


Fig.15 Storage and fall times versus applied reverse gate voltage; inductive load; $I_T = 10$ A; $I_G = 0.5$ A; $L_G = 0.4 \mu H$; $T_j = 25^\circ C$; maximum values.

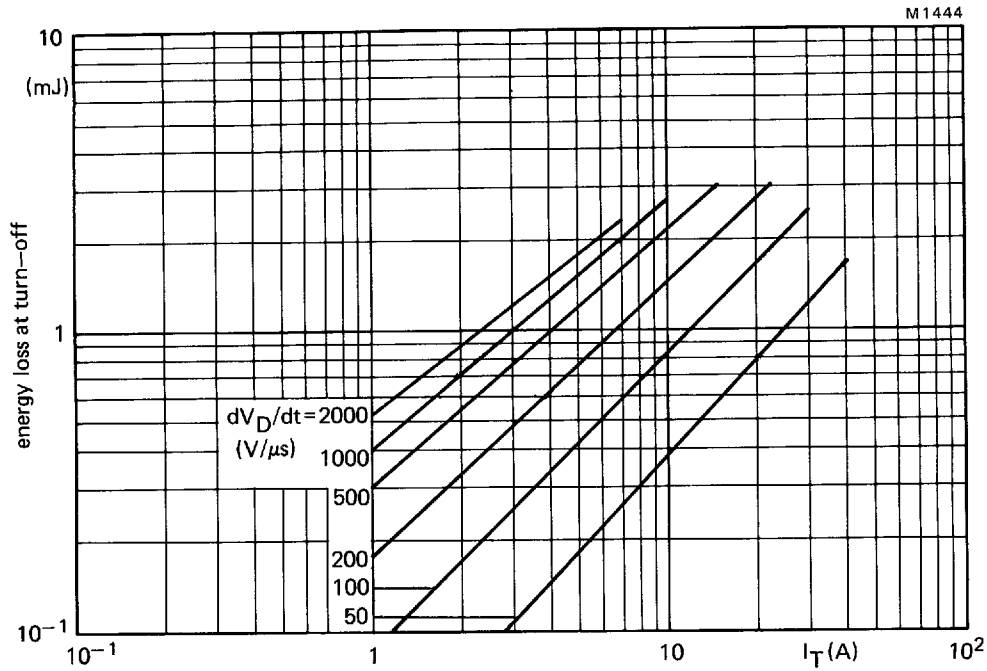


Fig.16 Maximum energy loss at turn-off (per cycle) as a function of anode current and applied dV_D/dt (calculated from I_T/C_S); dV_D/dt linear up to $V_{Dmax} = 600$ V; $V_{GR} = 10$ V; $I_G = 0.5$ A; $L_G \leq 0.5 \mu$ H; $L_S \leq 0.25 \mu$ H; $T_j = 120$ °C.

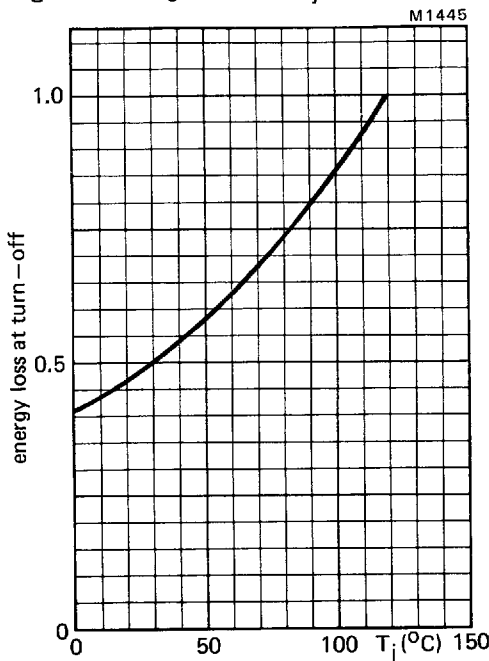


Fig.17 Energy loss at turn off as a function of junction temperature; $I_G = 0.5$ A; $V_{GR} = 10$ V. Normalised to $T_j = 120$ °C.